CategoryTOSHIBA Field Effect Transistor Silicon N Channel MOS Type/Category

SSM3K12T

DC-DC Converter High Speed Switching Applications

- Small Package
- Low ON-resistance $: R_{on} = 95 \text{ m}\Omega \text{ (max)} (@V_{GS} = 10 \text{ V})$

 $: R_{on} = 145 \text{ m}\Omega \text{ (max)} (@V_{GS} = 4.5 \text{ V})$

High speed

: t_{on} = 21 ns : t_{off} = 16 ns

Maximum Ratings (Ta = 25°C)

Characteristic		Symbol		Rating	Unit	
Drain-Source voltage		V _{DS}		30	V	
Gate-Source voltage		V _{GSS}		±20	V	
Drain current	DC		I _D	3.0	А	
	Pulse	I _{DP}	(Note 2)	6.0	~	
Drain power dissipation (Ta = 25°C)		P _D (Note 1)		0.7	W	
			t = 10 s	1.25	vV	
Channel temperature		T _{ch}		150	°C	
Storage temperature range		T _{stg}		-55~150	°C	

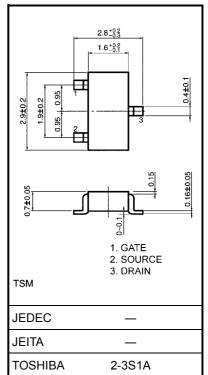
Note 1: Mounted on FR4 board (25.4 mm \times 25.4 mm \times 1.6 t, Cu pad: 645 mm²)

Note 2: The pulse width limited by max channel temperature.

Handling Precaution

When handling individual devices (which are not yet mounted on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

The Channel-to-Ambient thermal resistance R_{th} (ch-a) and the drain power dissipation PD vary according to the board material, board area, board thickness and pad area, and are also affected by the environment in which the product is used. When using this device, please take heat dissipation fully into account.



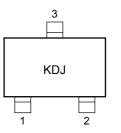
Weight: 10 mg (typ.)

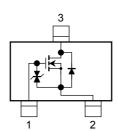
Unit: mm

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Marking

Equivalent Circuit





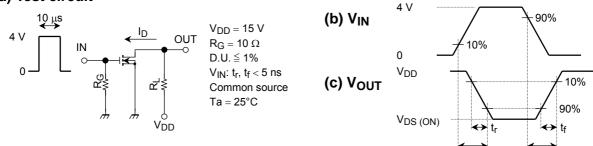
Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS}=\pm 16~V,~V_{DS}=0$	_		±1	μA
Drain-Source breakdown voltage		V (BR) DSS	$I_D = 1 \text{ mA}, V_{GS} = 0$	30		_	V
Drain Cut-off current		I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0$	_		1	μA
Gate threshold voltage		V _{th}	$V_{DS} = 5 \text{ V}, \text{ I}_{D} = 0.1 \text{ mA}$	1.1		1.8	V
Forward transfer admittance		Y _{fs}	$V_{DS} = 5 \text{ V}, \text{ I}_{D} = 1.5 \text{ A}$ (Note 3)	1.8	3.2	_	S
Drain-Source ON resistance		R _{DS} (ON)	$I_D = 1.5 \text{ A}, V_{GS} = 10 \text{ V}$ (Note 3)	_	78	95	mΩ
			$I_D = 1.5 \text{ A}, V_{GS} = 4.5 \text{ V}$ (Note 3)	_	117	145	
			$I_D = 1.5 \text{ A}, V_{GS} = 4.0 \text{ V}$ (Note 3)	_	135	175	
Total gate charge		Qg	$V_{DD} = 24 \text{ V}, \text{ I}_{D} = 3 \text{ A}, \text{ V}_{GS} = 4 \text{ V}$	_	2.6	_	nC
Input capacitance		C _{iss}	$V_{DS}=15~V,~V_{GS}=0,~f=1~MHz$	_	120	_	pF
Reverse transfer capacitance		C _{rss}	$V_{DS}=15~V,~V_{GS}=0,~f=1~MHz$	_	20	_	pF
Output capacitance		C _{oss}	$V_{DS}=15~V,~V_{GS}=0,~f=1~MHz$	_	68	_	pF
Switching time	Rise time	t _r		_	13	_	
	Turn-on time	t _{on}	V _{DD} = 15 V, I _D = 1.5 A		21	_	ns
	Fall time	t _f	$V_{GS} = 0~4 V, R_G = 10 \Omega$	_	3.6	—	
	Turn-off time	t _{off}	1	_	16	—	

Note 3 : Pulse test

Switching Time Test Circuit

(a) Test circuit



Precaution

 V_{th} can be expressed as voltage between gate and source when low operating current value is I_D = 100 μA for this product. For normal switching operation, V_{GS} (on) requires higher voltage than V_{th} and V_{GS} (off) requires lower voltage than V_{th} .

(relationship can be established as follows: $V_{\rm GS}~_{\rm (off)} < V_{th} < V_{\rm GS}~_{\rm (on)}$)

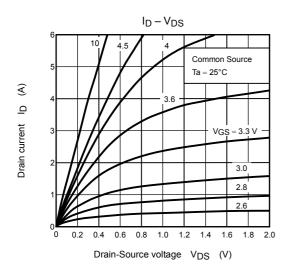
Please take this into consideration for using the device.

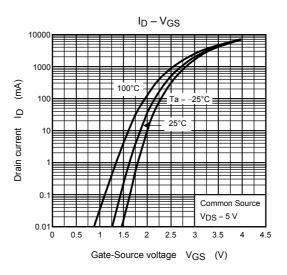
 $V_{\rm GS}$ recommended voltage of 4 V or higher to turn on this product.

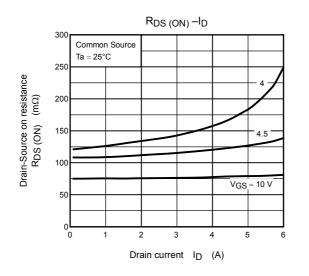
toff

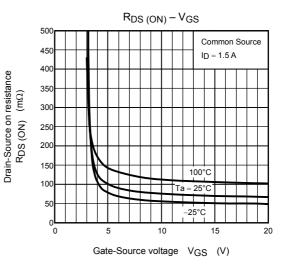
t_{on}

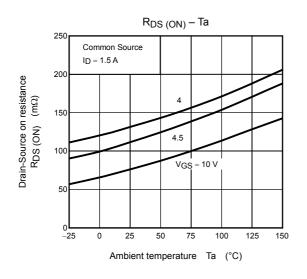
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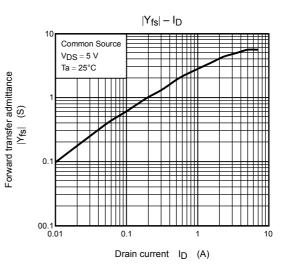




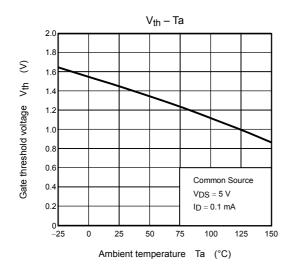


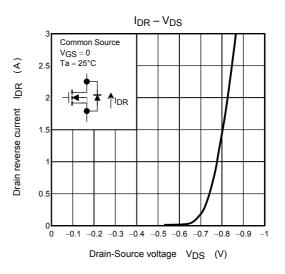


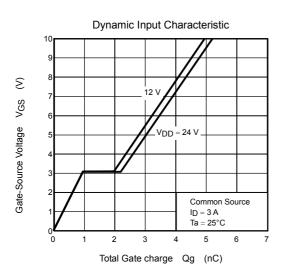


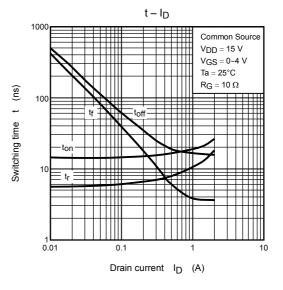


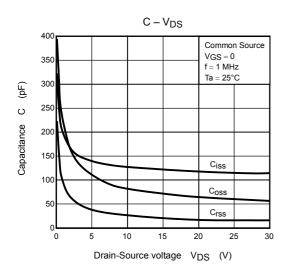
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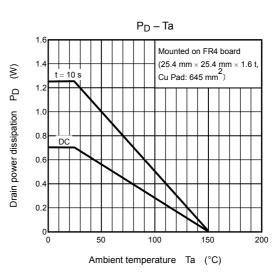


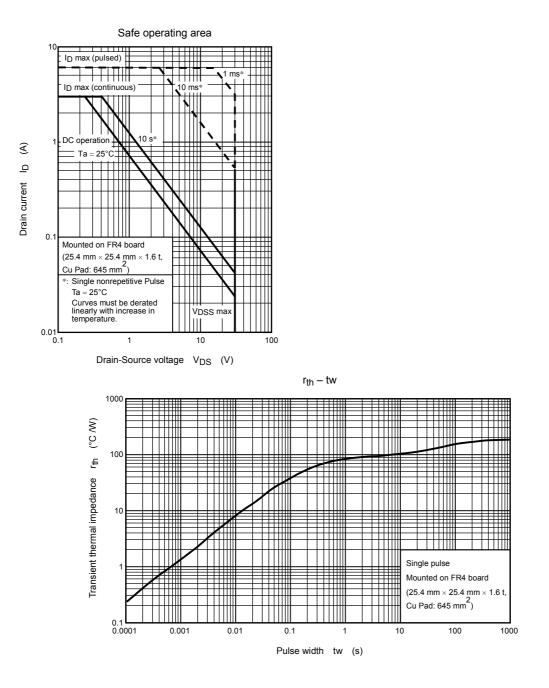












RESTRICTIONS ON PRODUCT USE

Handbook" etc.,

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